

Notice of References Cited	Application/Control No. 10/031,081	Applicant(s)/Patent Under Reexamination TERASAKI ET AL.	
	Examiner Bernard E Souw	Art Unit 2881	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,051,585	09-1991	Koshishiba et al.	250/306
	C	US-5,432,347	07-1995	Coene, Willem M. J. M.	250/307
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	M	US-			

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NON-PATENT DOCUMENTS

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	U	Terasaki et al., Microsc. Microanal. 8 (2002) pp. 35-39
	V	Kaneda et al., J. Phys. Chem. B 106 (2002) pp. 1256-1266
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.